



INTERNATIONAL APPLICATION PUBLISHED UNDER THE PATENT COOPERATION TREATY (PCT)

(51) International Patent Classification ⁶ : G11C	A2	(11) International Publication Number: WO 97/20316
		(43) International Publication Date: 5 June 1997 (05.06.97)

(21) International Application Number: PCT/IL96/00171

(22) International Filing Date: 28 November 1996 (28.11.96)

(30) Priority Data:

116220 30 November 1995 (30.11.95) IL

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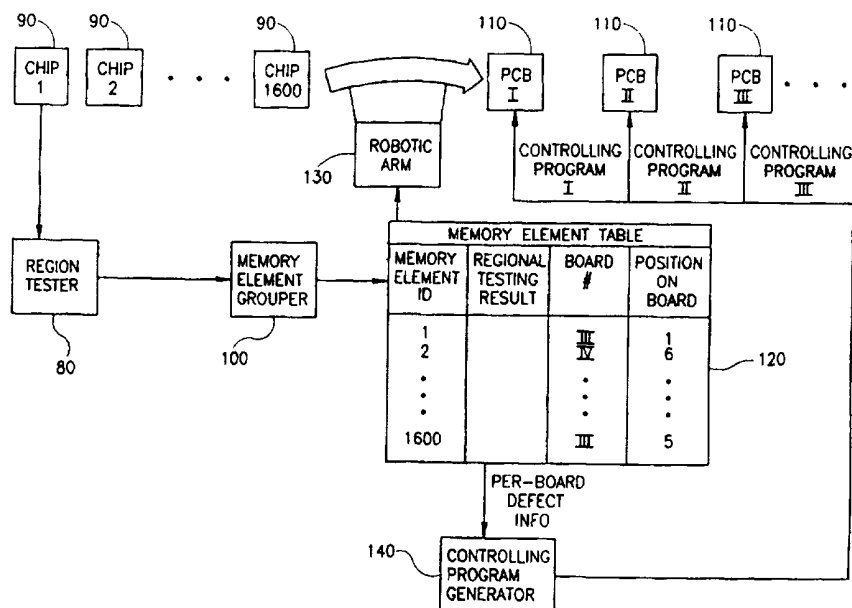
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(81) Designated States: CN, JP, KR, US, European patent (AT, BE, CH, DE, DK, ES, FI, FR, GB, GR, IE, IT, LU, MC, NL, PT, SE).

Published*Without international search report and to be republished upon receipt of that report.*

(54) Title: AUTOMATED PROCESS FOR GENERATING BOARDS FROM DEFECTIVE CHIPS



(57) Abstract

An automated process for generating memory systems from a population of memory elements including non-perfect memory elements, the process comprising testing regions within each non-perfect memory element for defective cells and generating a regional testing result for each non-perfect memory element; grouping the memory elements into a plurality of sets based on the regional testing results; and automatically generating a controlling program for a programmable controller for each memory system incorporating at least one of the plurality of sets.